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Title: Structural and Optical Properties of Silicon Nanocrystals Embedded in Silicon Carbide: Comparison of Single Layers and Multilayer Structures



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Highlights:

- Si nanocrystal size control in a SiC matrix achieved by Si content variation.
- We proved sublayer intermixing in Si_xC_{1-x}/SiC multilayer during annealing.
- Excess Si in SiC hinders SiC crystallisation.
- We performed a comparison between Si_xC_{1-x}/SiC multilayers and Si_xC_{1-x} single layers.
- Si nanocrystal size correlates with the E_{04} bandgap.

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